



4/6/2011

**PRODUCT RELIABILITY REPORT  
FOR**

**MAX66120, Rev B2**

**Maxim Integrated Products**

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**Conclusion:**

The following qualification successfully meets the quality and reliability standards required of all Maxim products:

MAX66120, Rev B2

In addition, Maxim's continuous reliability monitor program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards. The current status of the reliability monitor program can be viewed at <http://www.maxim-ic.com/TechSupport/dsreliability.html>.

**Device Description:**

A description of this device can be found in the product data sheet. You can find the product data sheet at [http://dbserv.maxim-ic.com/l\\_datasheet3.cfm](http://dbserv.maxim-ic.com/l_datasheet3.cfm).

**Reliability Derating:**

The Arrhenius model will be used to determine the acceleration factor for failure mechanisms that are temperature accelerated.

$AfT = \exp((Ea/k) * (1/Tu - 1/Ts)) = tu/ts$   
AfT = Acceleration factor due to Temperature  
tu = Time at use temperature (e.g. 55°C)  
ts = Time at stress temperature (e.g. 125°C)  
k = Boltzmann's Constant ( $8.617 \times 10^{-5}$  eV/°K)  
Tu = Temperature at Use (°K)  
Ts = Temperature at Stress (°K)  
Ea = Activation Energy (e.g. 0.7 eV)

The activation energy of the failure mechanism is derived from either internal studies or industry accepted standards, or activation energy of 0.7eV will be used whenever actual failure mechanisms or their activation energies are unknown. All deratings will be done from the stress ambient temperature to the use ambient temperature.

An exponential model will be used to determine the acceleration factor for failure mechanisms, which are voltage accelerated.

$AfV = \exp(B * (Vs - Vu))$   
AfV = Acceleration factor due to Voltage  
Vs = Stress Voltage (e.g. 7.0 volts)  
Vu = Maximum Operating Voltage (e.g. 5.5 volts)  
B = Constant related to failure mechanism type (e.g. 1.0, 2.4, 2.7, etc.)

The Constant, B, related to the failure mechanism is derived from either internal studies or industry accepted standards, or a B of 1.0 will be used whenever actual failure mechanisms or their B are unknown. All deratings will be done from the stress voltage to the maximum operating voltage. Failure rate data from the operating life test is reported using a Chi-Squared statistical model at the 60% or 90% confidence level (Cf).

The failure rate, Fr, is related to the acceleration during life test by:

$Fr = X / (ts * AfV * AfT * N * 2)$   
X = Chi-Sq statistical upper limit  
N = Life test sample size

Failure Rates are reported in FITs (Failures in Time) or MTTF (Mean Time To Failure). The FIT rate is related to MTTF by:

$$\text{MTTF} = 1/\text{Fr}$$

NOTE: MTTF is frequently used interchangeably with MTBF.

The calculated failure rate for this device/process is:

**FAILURE RATE:**                      **MTTF (YRS):**                      **87112**                      **FITS:**                      **1.3**  
**DEVICE HOURS:**                      **699223642**                      **FAILS:**                      **0**

Only data from Operating Life or similar stresses are used for this calculation.

The parameters used to calculate this failure rate are as follows:

**Cf: 60%**                      **Ea: 0.7**                      **B: 0**                      **Tu: 25**                      °C                      **Vu: 3.3**                      Volts

The reliability data follows. At the start of this data is the device information. The next section is the detailed reliability data for each stress. The reliability data section includes the latest data available and may contain some generic data. **Bold** Product Number denotes specific product data.

#### Device Information:

Process: SA E35W-0.5um, 5V CMOS with embedded Array EEPROM, embedded RSE EEPROM, 18V CMOS, VNPN, P2-P1 Cap, LVMOSCAP, HVMOSCAP, Varactor Cap, NTC poly R's, 3LM, M3 Laser Fuses  
Passivation: TEOS Oxide-Nitride Passivation  
Die Size: 85.03937 x 125.984252  
Number of Transistors: 131333  
Interconnect: Aluminum / 0.5% Copper  
Gate Oxide Thickness: 120 Å

#### ESD HBM

| DESCRIPTION     | DATE CODE/PRODUCT/LOT | CONDITION                              | READPOIN | QTY   | FAILS    | FA#     |
|-----------------|-----------------------|--|----------|-------|----------|---------|
| ESD SENSITIVITY | 1004 <b>MAX66140</b>  | WJ050342AB EOS/ESD S5.1 HBM 500 VOLTS  | 1        | PUL'S | 3        | 0       |
| ESD SENSITIVITY | 1004 <b>MAX66140</b>  | WJ050342AB EOS/ESD S5.1 HBM 1000 VOLTS | 2        | PUL'S | 3        | 0       |
| ESD SENSITIVITY | 1004 <b>MAX66140</b>  | WJ050342AB EOS/ESD S5.1 HBM 2000 VOLTS | 3        | PUL'S | 3        | 0       |
| ESD SENSITIVITY | 1004 <b>MAX66140</b>  | WJ050342AB EOS/ESD S5.1 HBM 4000 VOLTS | 4        | PUL'S | 3        | 0       |
| ESD SENSITIVITY | 1004 <b>MAX66140</b>  | WJ050342AB EOS/ESD S5.1 HBM 8000 VOLTS | 5        | PUL'S | 3        | 3 No FA |
| <b>Total:</b>   |                       |  |          |       | <b>3</b> |         |

#### LATCH-UP

| DESCRIPTION   | DATE CODE/PRODUCT/LOT | CONDITION                             | READPOIN | QTY | FAILS    | FA# |
|---------------|-----------------------|---------------------------------------|----------|-----|----------|-----|
| LATCH-UP I    | 1004 <b>MAX66140</b>  | WJ050342AB JESD78A, I-TEST 85C        |          | 6   | 0        |     |
| LATCH-UP V    | 1004 <b>MAX66140</b>  | WJ050342AB JESD78A, V-SUPPLY TEST 25C |          | 6   | 0        |     |
| <b>Total:</b> |                       |                                       |          |     | <b>0</b> |     |

| DESCRIPTION       | DATE | CODE/PRODUCT/LOT | CONDITION                   | READPOIN | QTY | FAILS | FA# |
|-------------------|------|------------------|-----------------------------|----------|-----|-------|-----|
| HIGH TEMP OP LIFE | 0845 | DS2431           | WJ943331AB 125C, 5.25 VOLTS | 1000 HRS | 77  | 0     |     |
| HIGH TEMP OP LIFE | 0845 | DS2431           | WJ943238Q 125C, 5.25 VOLTS  | 1000 HRS | 77  | 0     |     |
| HIGH TEMP OP LIFE | 0846 | DS28EC20         | WJ941331D 125C, 5.25 VOLTS  | 1000 HRS | 77  | 0     |     |
| HIGH TEMP OP LIFE | 0846 | DS28EC20         | WJ942984PB 125C, 5.25 VOLTS | 1000 HRS | 77  | 0     |     |
| HIGH TEMP OP LIFE | 0846 | DS28EC20         | WJ943330BB 125C, 5.25 VOLTS | 1000 HRS | 77  | 0     |     |
| HIGH TEMP OP LIFE | 0846 | DS28EC20         | WJ942984PB 125C, 5.25 VOLTS | 408 HRS  | 80  | 0     |     |
| HIGH TEMP OP LIFE | 0848 | DS2431           | WJ943235BB 125C, 5.25 VOLTS | 1000 HRS | 77  | 0     |     |
| HIGH TEMP OP LIFE | 0951 | DS2430A          | WH048838A 125C, 5.25 VOLTS  | 192 HRS  | 50  | 0     |     |
| HIGH TEMP OP LIFE | 1004 | <b>MAX66140</b>  | WJ050342AB 125C, 3.3 VOLTS  | 192 HRS  | 45  | 0     |     |
| HIGH TEMP OP LIFE | 1009 | DS1624           | WJ048844BB 125C, 5.5 VOLTS  | 192 HRS  | 77  | 0     |     |
| HIGH TEMP OP LIFE | 1013 | DS2431           | WJ052466AB 150C, 5.25 VOLTS | 408 HRS  | 50  | 0     |     |
| HIGH TEMP OP LIFE | 1013 | DS2431           | WJ052268AB 150C, 5.25 VOLTS | 408 HRS  | 50  | 0     |     |
| HIGH TEMP OP LIFE | 1014 | DS2431           | WJ052527AB 150C, 5.25 VOLTS | 408 HRS  | 50  | 0     |     |
| HIGH TEMP OP LIFE | 1039 | MAX31722         | ZJ148849DB 125C, 3.7V (PSA) | 192 HRS  | 48  | 0     |     |

|               |               |           |        |     |
|---------------|---------------|-----------|--------|-----|
| FAILURE RATE: | MTTF (YRS):   | 87112     | FITS:  | 1.3 |
|               | DEVICE HOURS: | 699223642 | FAILS: | 0   |